



Novel Ideas for Infrared Thermography also Applied in Integrated Approaches

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Message from the Guest Editors

This Special Issue is devoted to the application of the infrared thermography (IRT) method. The use of combined approaches are also welcomed. The authors should demonstrate that the part of IRT is predominant in the works, and it is direct towards the implementation of new ideas. The participation of leading scientists is important to guide the reader and users towards a world seen at infrared. This is useful in process temperature-dependent linked to the civil, mechanical, biomedical and so on. Particularly welcome will be works that validate preliminary numerical simulations. In situ applications are considered as laboratory measurements. The message is based on IRT as a non-destructive, non-invasive, and non-intrusive method useful to analyze thermal responses.

Deadline for manuscript submissions:

closed (31 January 2018)

- Infrared thermography
- Non-destructive testing
- Advanced image processing
- Defect detection
- Heat transfer
- Measurement uncertainty
- Thermographic numerical simulations
- Infrared vision
- Defect depth retrieval
- Qualitative and quantitative analyses





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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